

In Situ XRD Investigation on Phase Transformation of CIGS Alloyed Compound during Heat Treatment

Shin-Hong Chang (張士淞)¹, Chih-Chung Wu (吳致中)¹, Bing-Joe Hwang (黃炳照)¹,
Hwo-Shuenn Sheu (許火順)², and Wei-Tsung Chuang (莊偉綜)²

¹Department of Chemical Engineering, National Taiwan University of Science and Technology, Taipei, Taiwan

²National Synchrotron Radiation Research Center, Hsinchu, Taiwan

Despite of the significant advances made so far in solar energy conversion technology, the crystalline silicon-based photovoltaic (PV) modules still had a problem of high-manufacturing cost; hence, the development of the low-priced PV modules became an important issue. The thin-film Cu(In,Ga)Se₂ (CIGS) solar cells with high photovoltaic conversions had highly potential among these solar cells, but the costs of thin-film CIGS solar cells fabricated by the vacuum process (co-evaporation, sputtering) was high. Therefore, the cost reductions by establishing non-vacuum processes for manufacturing thin-film CIGS solar cells become a major task.

Fabrication of CIGS alloyed compound with chalcopyrite phase could be achieved by the knowledge obtained from the phase transformation and formation mechanism. However, the formation mechanism could be studied by in-situ XAS; the structure parameter corresponding to the chemical environment could be extracted, such as: local coordination of absorbing atom, bond distance. These information led us to establish the formation mechanism of CIGS alloyed compound in the synthesis system. The phase transformation of synthesis sample under heat treatment could be studied by in-situ XRD.

The synthesized ternary precursor by solvo-thermal method (CGS and CIS) were packed into capillary tube (shown in Figure.1). The precursor were heated with the heating rate 10 °Cmin⁻¹ by heating gun and collected data for each 10 min from 30°C to 600°C.

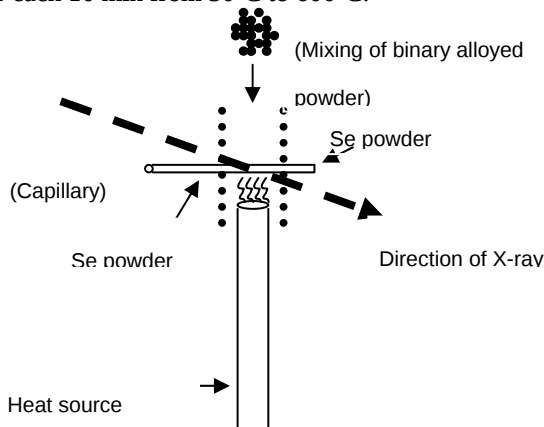


Figure 1. Scheme of in-situ XRD experiment under heat treatment

The XRD pattern indicated that mixed ternary powder at 150 °C had (112), (220), (312), (400) and (316) orientations. The peaks of (316), (400) orientation were disappeared and the (112), (220) and (312) were shifted toward higher angles with the increasing temperature due to the migration of Ga atom into CIS lattice caused the lattice expansion. Finally, at 600°C, the chalcopyrite phase of CIGS was obtained

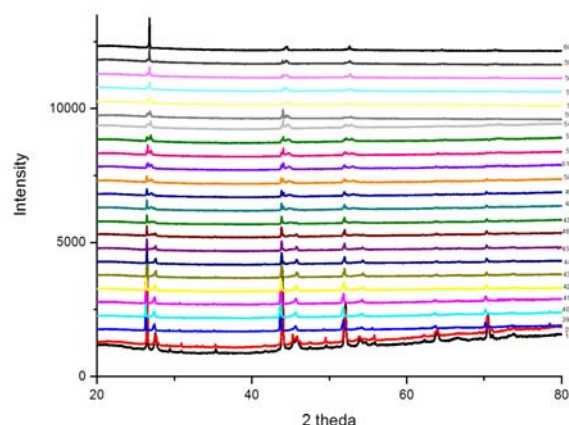


Figure 2. In-situ XRD pattern of phase transformation of mixed CGS and CIS alloy compound under heat treatment.